



REPORT No. : SZ16100102E02

# FCC TEST REPORT

**APPLICANT** : Fourier Systems Inc  
**PRODUCT NAME** : Tablet PC  
**MODEL NAME** : ENTAB2,einstein II+,E892  
**TRADE NAME** : einstein  
**BRAND NAME** : einstein  
**FCC ID** : 2AAKDEINSX02  
**STANDARD(S)** : 47 CFR Part 15 Subpart B  
**TEST DATE** : 2016-11-04 to 2016-11-14  
**ISSUE DATE** : 2016-11-15



SHENZHEN MORLAB COMMUNICATIONS TECHNOLOGY Co., Ltd.

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## DIRECTORY

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| Change History |            |                   |
|----------------|------------|-------------------|
| Issue          | Date       | Reason for change |
| 1.0            | 2016-11-15 | First edition     |

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## Test Report Declaration

|                      |   |
|----------------------|---|
| Applicant            | Fourier Systems Inc   |
| Applicant Address    | 16 Hamelacha Street, Rosh Ha'ayin 48091, Israel                                       |
| Manufacturer         | Shenzhen Chuangwei Electronic Appliance Tech Co., Ltd.                                |
| Manufacturer Address | 4/F,6/F South, Skyworth Industrial Park, Shiyuan Bao'an District, Shenzhen, Guangdong |
| Product Name         | Tablet PC   |
| Model Name           | ENTAB2,einstein II+,E892  |
| Brand Name           | einstein  |
| HW Version           | V10   |
| SW Version           | 5.1.1   |
| Test Standards       | 47 CFR Part 15 Subpart B  |
| Test Result          | PASS  |

Tested by : Wu Zhongwen  
Wu Zhongwen (Test Engineer)

Reviewed by : Xiao Xiong  
Xiao Xiong (EMC Manager)

Approved by : Andy Yeh  
Andy Yeh (Technology Manager)



# 1. Technical Information

Note: Provided by applicant

## 1.1. Applicant Information

Company: Fourier Systems Inc  
Address: 16 Hamelacha Street, Rosh Ha'ayin 48091, Israel

## 1.2. Equipment under Test (EUT) Description

|                              |   |
|------------------------------|---|
| <b>EUT Type:</b>             | Tablet PC                               |
| <b>Serial No:</b>            | (N/A, marked #1 by test site)           |
| <b>Hardware Version:</b>     | V10                                     |
| <b>Software Version:</b>     | 5.1.1                                   |
| <b>Power supply:</b>         | <b>Battery</b>                          |
| Brand Name:                  | N/A                                     |
| Model No.:                   | 3377102-2P                              |
| Serial No.:                  | (N/A ,marked #1 by test site)           |
| Capacity:                    | 6200mAh                                 |
| Rated Voltage:               | 3.7V                                    |
| Charge Limit:                | 4.2V                                    |
| <b>Ancillary Equipment :</b> | <b>AC Adapter (Charger for Battery)</b> |
| Brand Name:                  | N/A                                     |
| Model No.:                   | KSA29B0500200D5                         |
| Serial No.:                  | (N/A. marked #1 by test site)           |
| Rated Input:                 | ~ 100-240V, 50/60Hz,500mA               |
| Rated Output:                | = 5.0V, 2.0A                            |

### NOTE:

1. The EUT is equipped with a T-Flash slot, a Micro USB port, four extended ports and a HDMI port which can be connected to ancillary equipments.
2. The terminal product ENTAB2, einstein II+,E892 have the same hardware, the same power adapter and housing. The main differences are that they have different color or brand name or model or back cover, but has no influence on the safety, EMC and RF test.



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3. For a more detailed description, please refer to specification or user's manual supplied by the applicant and/or manufacturer.

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## 2. Test Results

### 2.1. Applied Reference Documents

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

| No. | Identity       | Document Title          |
|-----|----------------|-------------------------|
| 1   | 47 CFR Part 15 | Radio Frequency Devices |

Test detailed items/section required by FCC rules and results are as below:

| No. | Section | Description        | Test Date  | Result |
|-----|---------|--------------------|------------|--------|
| 1   | 15.107  | Conducted Emission | 2016.11.11 | PASS   |
| 2   | 15.109  | Radiated Emission  | 2016.11.11 | PASS   |

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4-2014.



### 3. Test Conditions Setting

#### 3.1. Test Mode

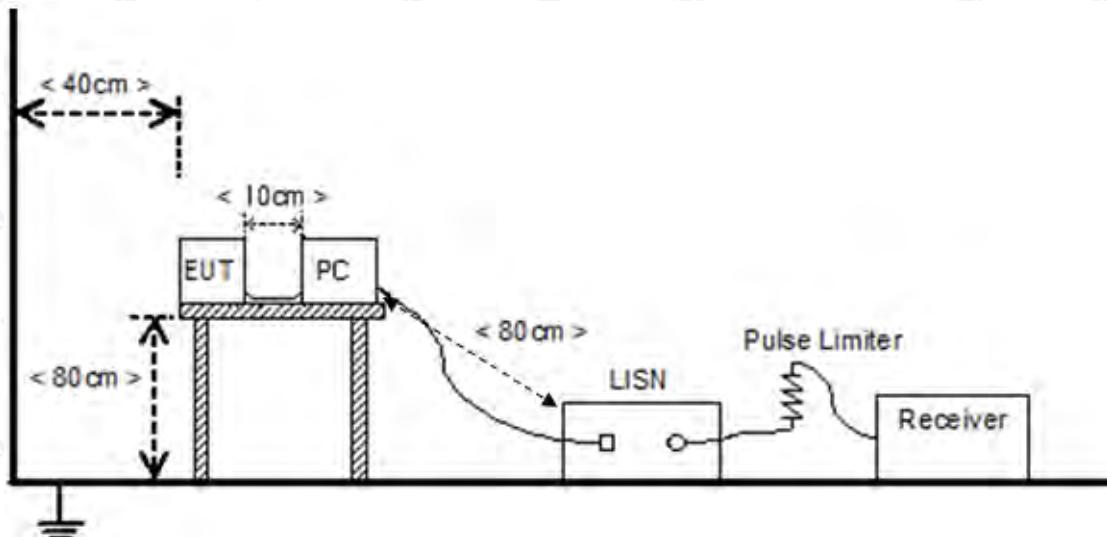
|   |   |
|---|---|
| 1 | <b>The first test mode (Charging)</b><br>The EUT configuration of the emission tests is EUT + Adapter.<br>During the measurement, the EUT was connected with the Adapter and kept charging by the Adapter, meanwhile, it was kept rated output and working normally.  |
| 2 | <b>The second test mode (Data Transmitting)</b><br>The EUT configuration of the emission tests is EUT + Battery + PC + T-Flash card.<br>During the test, the EUT embedded with a T-Flash card was connected with the PC, the EUT was charged by the PC, meanwhile the data was transmitted between the PC and the T-Flash Card of the EUT.                  |
| 3 | <b>The third test mode (Camera)</b><br>The EUT configuration of the emission tests is EUT + Battery + Charger + T-Flash Card<br>During the test, the camera function was active.  |
| 4 | <b>The fourth test mode (HDMI)</b><br>The EUT configuration of the emission tests is EUT + Battery + Charger + T-Flash Card + HDMI Device.<br>During the test, the EUT was charged by the charger, the EUT with a T-Flash card embedded was connected with a HDMI Device, the data was transmitted between the HDMI Device and the T-Flash Card of the EUT. |

NOTE: All test modes are performed, only the worst case (the first) is recorded in this report.

## 3.2. Test Setup and Equipments List

### 3.2.1. Conducted Emission

#### A. Test Setup:



The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides  $50\Omega/50\mu\text{H}$  of coupling impedance for the measuring instrument. A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

The power strip or extension cord has been investigated to make sure that the LISN integrity is maintained with respect to the impedance characteristics as prescribed in ANSI C63.4-2014 at Clause 4.3.

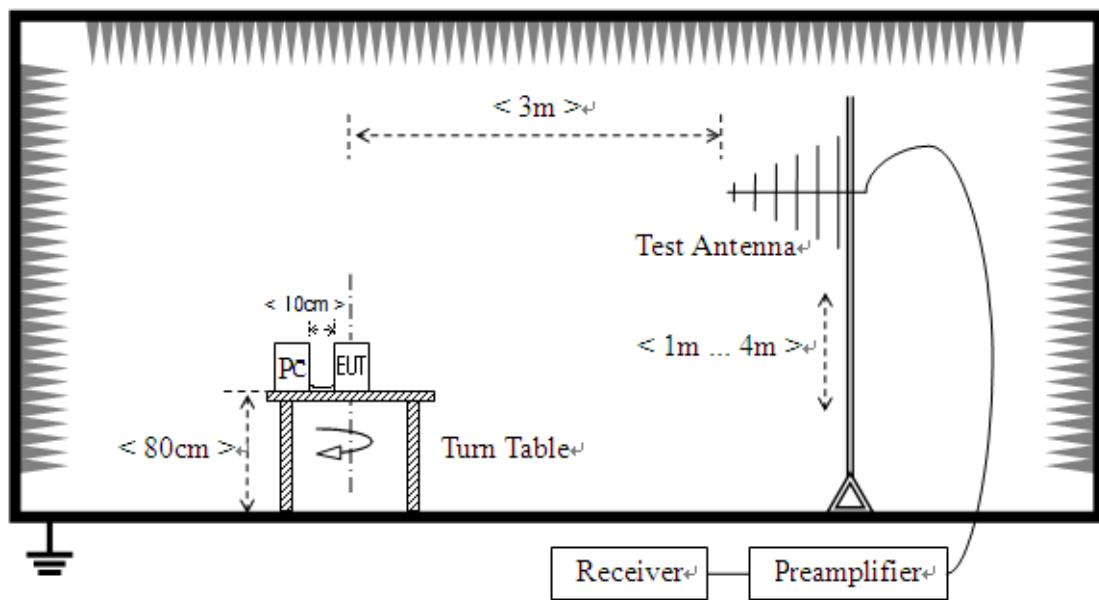
#### B. Equipments List:

| Description             | Manufacturer | Model       | Serial No. | Cal. Date  | Due. Date  |
|-------------------------|--------------|-------------|------------|------------|------------|
| Receiver                | Narda        | PMM 9060    | 001WX11001 | 2015.11.26 | 2016.11.25 |
| Receiver                | Narda        | PMM 9010    | 595WX11007 | 2016.01.13 | 2017.01.12 |
| LISN                    | Schwarzbeck  | NSLK 8127   | 812744     | 2016.01.13 | 2017.01.12 |
| Pulse Limiter<br>(20dB) | Schwarzbeck  | VTSD 9561-D | 9391       | 2016.01.13 | 2017.01.12 |

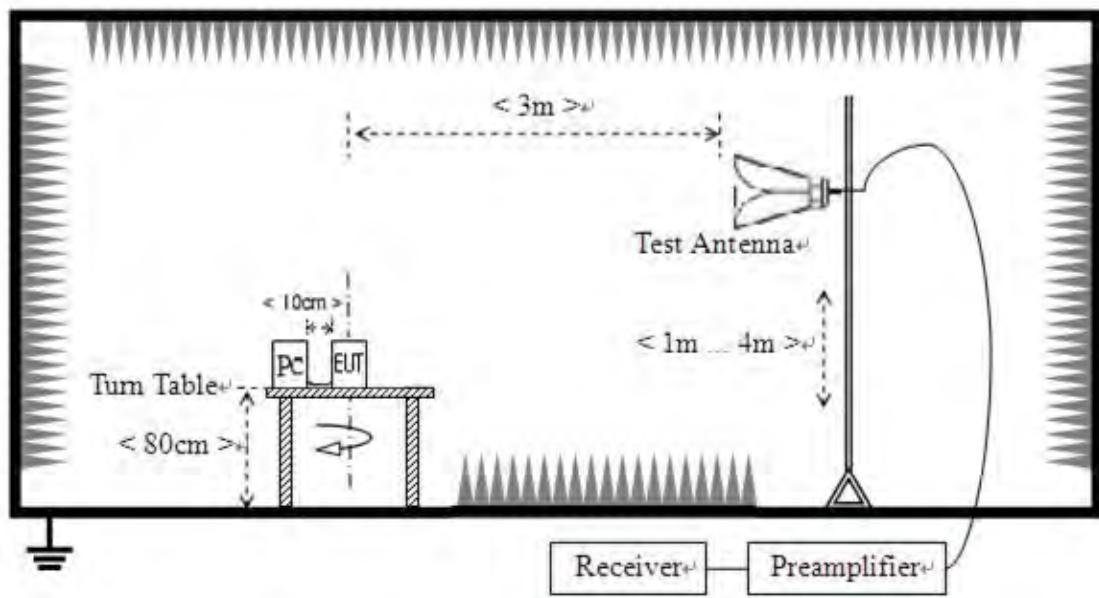
### 3.2.2. Radiated Emission

#### A. Test Setup:

1. For radiated emissions from 30MHz to1GHz



2. For radiated emissions above 1GHz





The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower.

For the test Antenna:

In the frequency range above 30MHz, Bi-Log Test Antenna (30MHz to 1GHz) and Horn Test Antenna (above 1GHz) are used. Test Antenna is 3m away from the EUT. Test Antenna height is varied from 1m to 4m above the ground to determine the maximum value of the field strength. The emission levels at both horizontal and vertical polarizations should be tested.

## B. Equipments List:

| Description           | Manufacturer | Model     | Serial No. | Cal. Date  | Due. Date  |
|-----------------------|--------------|-----------|------------|------------|------------|
| MXE EMIRceiver        | Agilent      | N9038A    | MY54130016 | 2016.01.13 | 2017.01.12 |
| Semi-Anechoic Chamber | Changning    | 9m*6m*6m  | N/A        | 2016.01.13 | 2017.01.12 |
| Test Antenna - Bi-Log | Schwarzbeck  | VULB 9163 | 9163-274   | 2016.01.13 | 2017.01.12 |
| Test Antenna - Horn   | Schwarzbeck  | BBHA9120C | 9120C-384  | 2016.01.13 | 2017.01.12 |



## 4. 47 CFR Part 15B Requirements

### 4.1. Conducted Emission

#### 4.1.1. Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a 50 $\mu$ H/50 $\Omega$  line impedance stabilization network (LISN).

| Frequency range<br>(MHz) | Conducted Limit (dB $\mu$ V) |          |
|--------------------------|------------------------------|----------|
|                          | Quasi-peak                   | Average  |
| 0.15 - 0.50              | 66 to 56                     | 56 to 46 |
| 0.50 - 5                 | 56                           | 46       |
| 5 - 30                   | 60                           | 50       |

NOTE:

- a) The limit subjects to the Class B digital device.
- b) The lower limit shall apply at the band edges.
- c) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50MHz.

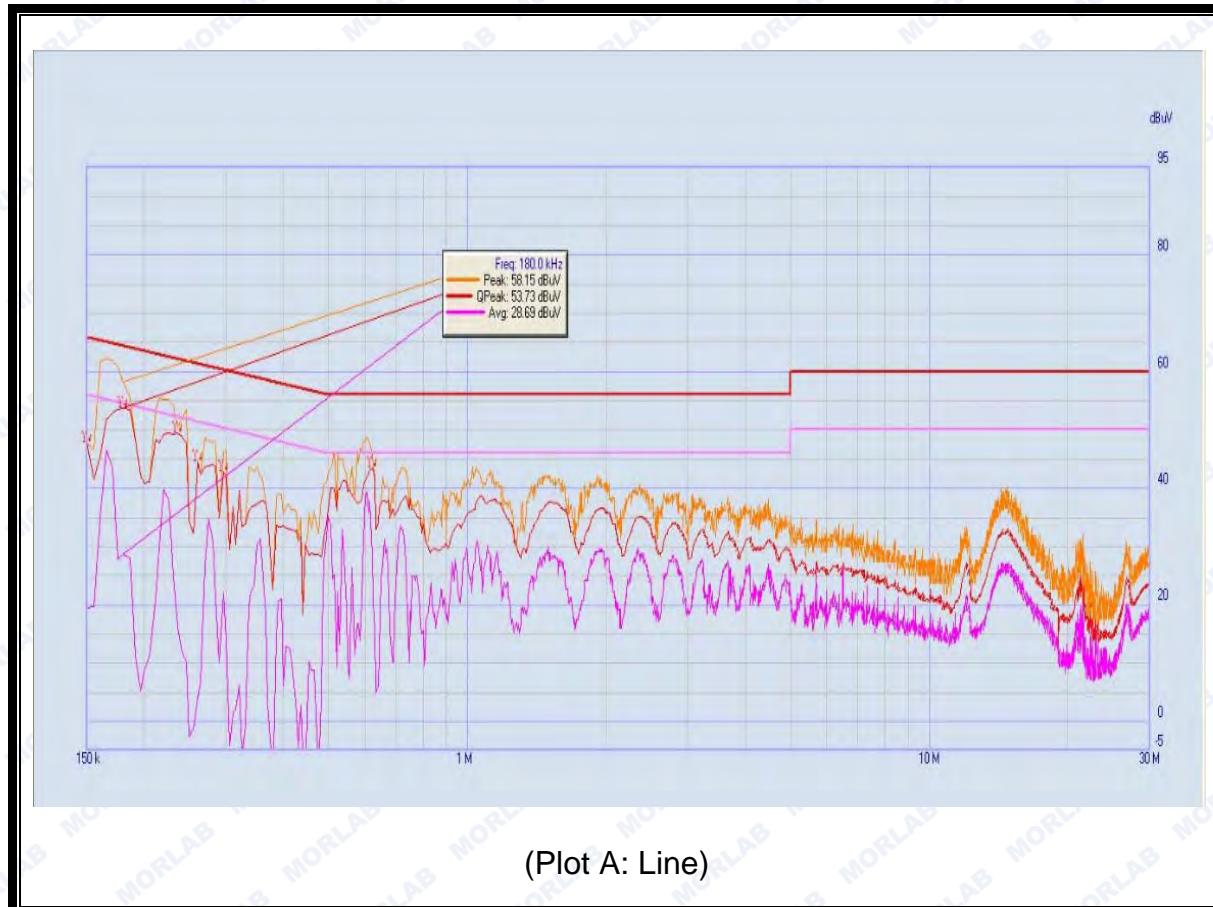
#### 4.1.2. Test Description

See section 3.2.1 of this report.

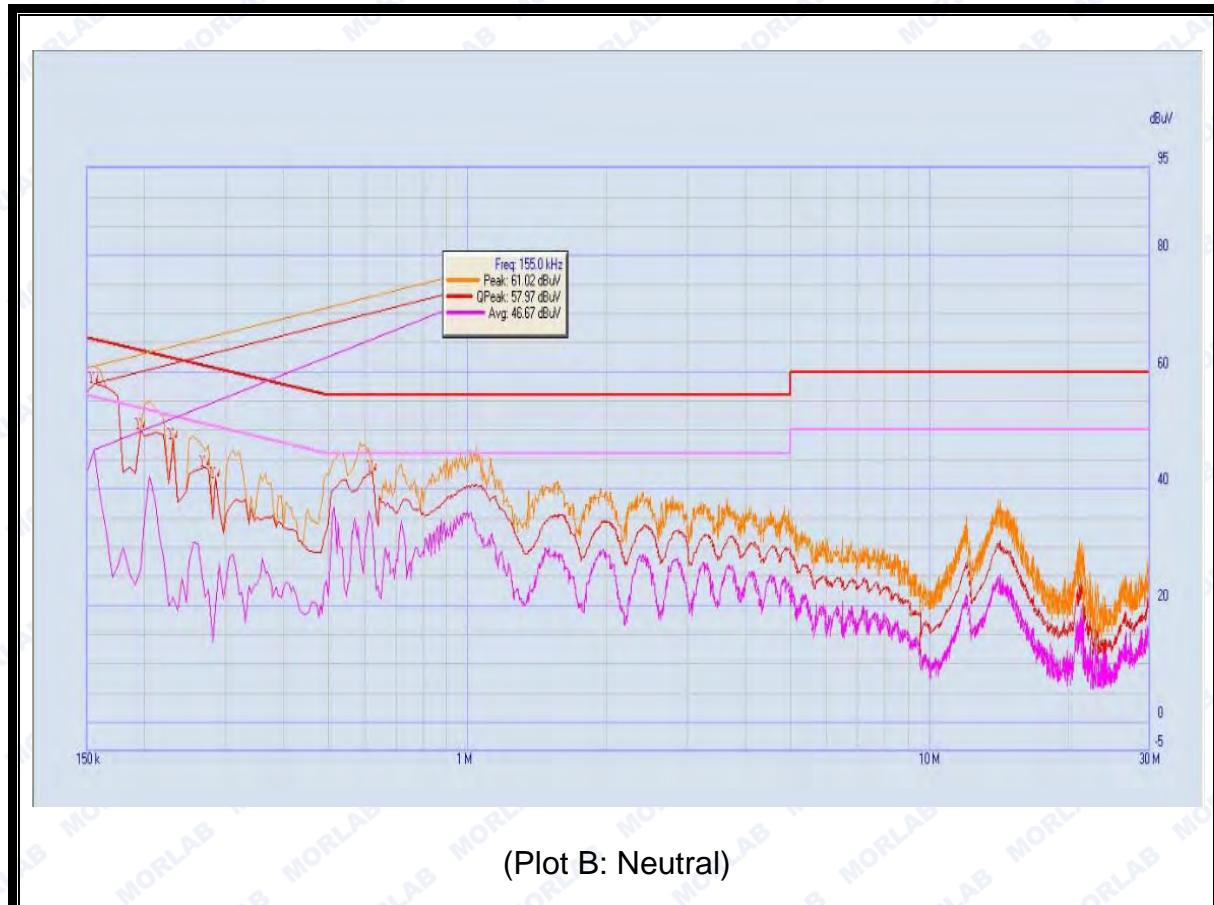
#### 4.1.3. Test Result

The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

#### A. Test Plot and Suspicious Points:



| NO. | Fre.<br>(MHz) | Emission Level (dB $\mu$ V) |         | Limit (dB $\mu$ V) |         | Power-line | Verdict |
|-----|---------------|-----------------------------|---------|--------------------|---------|------------|---------|
|     |               | Quai-peak                   | Average | Quai-peak          | Average |            |         |
| 1   | 0.15          | 47.82                       | 19.49   | 66.00              | 56.00   | Line       | PASS    |
| 2   | 0.18          | 53.73                       | 28.69   | 65.14              | 55.14   |            | PASS    |
| 3   | 0.235         | 49.52                       | 16.34   | 63.57              | 53.57   |            | PASS    |
| 4   | 0.26          | 44.51                       | 4.25    | 62.86              | 52.86   |            | PASS    |
| 5   | 0.295         | 42.88                       | 22.07   | 61.86              | 51.86   |            | PASS    |
| 6   | 0.62          | 43.43                       | 28.79   | 56.00              | 46.00   |            | PASS    |



| NO. | Fre.<br>(MHz) | Emission Level (dB $\mu$ V) |         | Limit (dB $\mu$ V) |         | Power-line | Verdict |
|-----|---------------|-----------------------------|---------|--------------------|---------|------------|---------|
|     |               | Quai-peak                   | Average | Quai-peak          | Average |            |         |
| 1   | 0.155         | 57.97                       | 46.67   | 65.86              | 55.86   | Neutral    | PASS    |
| 2   | 0.195         | 50.11                       | 26.04   | 64.71              | 54.71   |            | PASS    |
| 3   | 0.23          | 48.37                       | 21.37   | 63.71              | 53.71   |            | PASS    |
| 4   | 0.27          | 43.64                       | 21.47   | 62.57              | 52.57   |            | PASS    |
| 5   | 0.285         | 41.67                       | 19.66   | 62.14              | 52.14   |            | PASS    |
| 6   | 0.62          | 42.75                       | 33.96   | 56.00              | 46.00   |            | PASS    |

**Test Result: PASS**



## 4.2. Radiated Emission

### 4.2.1. Requirement

According to FCC section 15.109(a), the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

| Frequency range (MHz) | Field Strength Limitation at 3m Measurement Dist |                |
|-----------------------|--|----------------|
|                       | ( $\mu$ V/m)                                     | (dB $\mu$ V/m) |
| 30.0 - 88.0           | 100  | 20log 100      |
| 88.0 - 216.0          | 150  | 20log 150      |
| 216.0 - 960.0         | 200  | 20log 200      |
| Above 960.0           | 500  | 20log 500      |

As shown in FCC section 15.35(b), for frequencies above 1000MHz, the field strength limits are based on average detector. When average radiated emission measurements are specified in this part, including emission measurements below 1000MHz, there also is a limit on the radio frequency emissions, as measured using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit for the frequency being investigated unless a different peak emission limit is otherwise specified in the rules.

Note:

- 1) The tighter limit shall apply at the boundary between two frequency range.
- 2) Limitation expressed in dB $\mu$ V/m is calculated by 20log Emission Level( $\mu$ V/m).
- 3) If measurement is made at 3m distance, then F.S Limitation at 3m distance is adjusted by using the formula of  $Ld1 = Ld2 * (d2/d1)^2$ .

Example:

F.S Limit at 30m distance is 30 $\mu$ V/m, then F.S Limitation at 3m distance is adjusted as

$$Ld1 = L1 = 30\mu V/m * (10)^2 = 100 * 30\mu V/m$$

### 4.2.2. Test Description

See section 3.2.2 of this report.



#### 4.2.3. Frequency range of measurement

According to 15.33(b)(1), the frequency range of radiated measurement for the EUT is listed in the following table:

| Highest frequency generated or used in the device or on which the device operates or tunes (MHz) | Upper frequency of measurement range (MHz)                           |
|--|--|
| Below 1.705 .....  | 30.  |
| 1.705–108 .....  | 1000.  |
| 108–500 .....  | 2000.  |
| 500–1000 .....   | 5000.  |
| Above 1000 .....   | 5th harmonic of the highest frequency or 40 GHz, whichever is lower. |

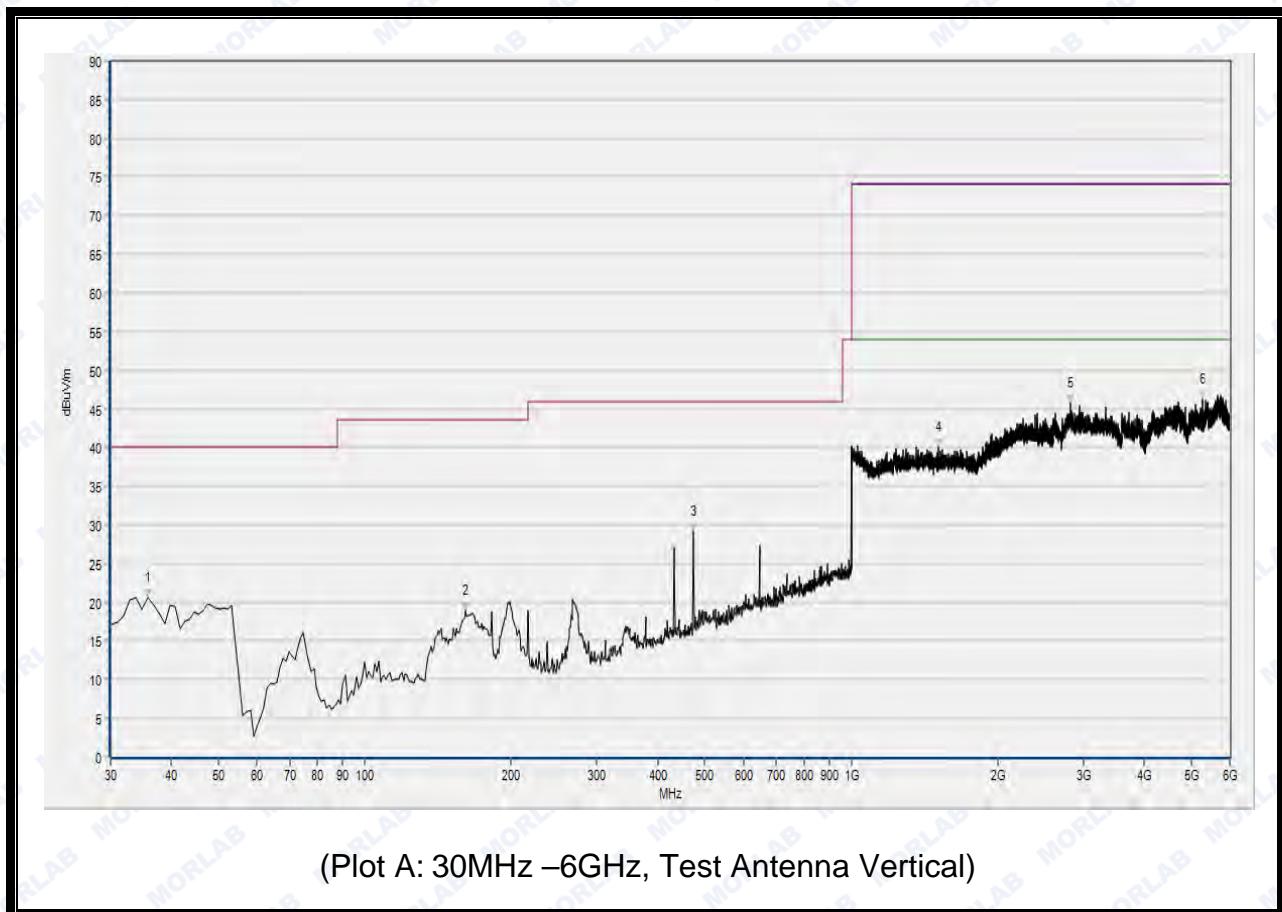
#### 4.2.4. Test Result

The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

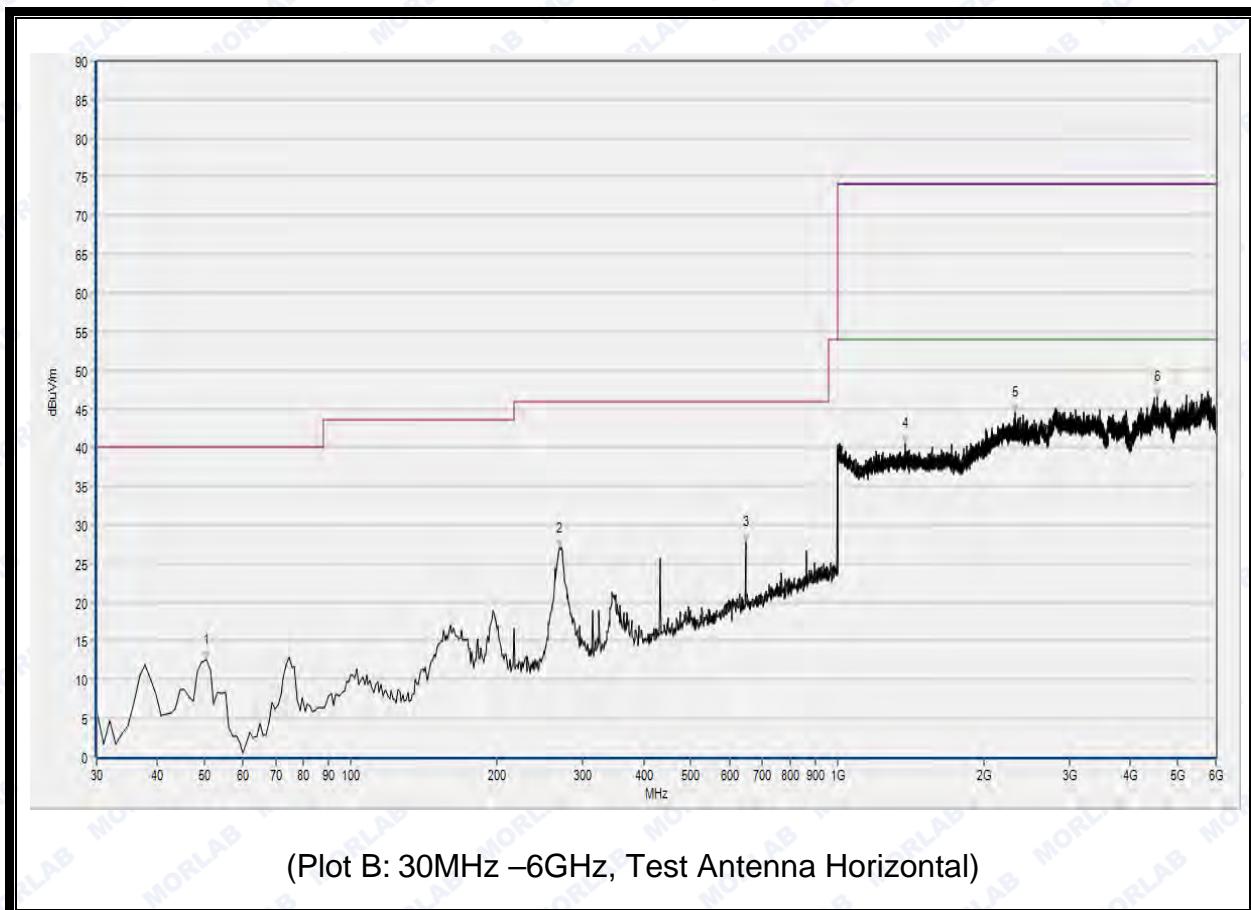
The amplitude of emissions(6GHz-12.5GHz) which are attenuated more than 20 dB below the permissible value need not be reported.

Note: All radiated emission tests were performed in X, Y, Z axis direction, and only the worst axis test condition was recorded in this test report.

##### A. Test Plots and Suspicious Points:



| No. | Fre.<br>MHz | Pk<br>dB $\mu$ V/m | QP<br>dB $\mu$ V/m | AV<br>dB $\mu$ V/m | Limit-PK<br>dB $\mu$ V/m | Limit-QP<br>dB $\mu$ V/m | Limit-AV<br>dB $\mu$ V/m | ANT | Verdict |
|-----|-------------|--------------------|--------------------|--------------------|--------------------------|--------------------------|--------------------------|-----|---------|
| 1   | 35.820      | N.A.               | 20.59              | N.A.               | N.A.                     | 40.00                    | N.A.                     | V   | PASS    |
| 2   | 160.950     | N.A.               | 18.93              | N.A.               | N.A.                     | 43.50                    | N.A.                     | V   | PASS    |
| 3   | 473.290     | N.A.               | 29.21              | N.A.               | N.A.                     | 46.00                    | N.A.                     | V   | PASS    |
| 4   | 1510.400    | 39.99              | N.A.               | 33.21              | 74.00                    | N.A.                     | 54.00                    | V   | PASS    |
| 5   | 2826.560    | 45.71              | N.A.               | 39.58              | 74.00                    | N.A.                     | 54.00                    | V   | PASS    |
| 6   | 5276.480    | 46.26              | N.A.               | 40.08              | 74.00                    | N.A.                     | 54.00                    | V   | PASS    |



| No. | Fre.<br>MHz | Pk<br>dB $\mu$ V/m | QP<br>dB $\mu$ V/m | AV<br>dB $\mu$ V/m | Limit-PK<br>dB $\mu$ V/m | Limit-QP<br>dB $\mu$ V/m | Limit-AV<br>dB $\mu$ V/m | ANT | Verdict |
|-----|-------------|--------------------|--------------------|--------------------|--------------------------|--------------------------|--------------------------|-----|---------|
| 1   | 50.370      | N.A.               | 12.50              | N.A.               | N.A.                     | 40.00                    | N.A.                     | H   | PASS    |
| 2   | 268.620     | N.A.               | 26.93              | N.A.               | N.A.                     | 46.00                    | N.A.                     | H   | PASS    |
| 3   | 647.890     | N.A.               | 27.83              | N.A.               | N.A.                     | 46.00                    | N.A.                     | H   | PASS    |
| 4   | 1378.133    | 40.52              | N.A.               | 34.70              | 74.00                    | N.A.                     | 54.00                    | H   | PASS    |
| 5   | 2318.933    | 44.53              | N.A.               | 38.02              | 74.00                    | N.A.                     | 54.00                    | H   | PASS    |
| 6   | 4558.400    | 46.52              | N.A.               | 40.31              | 74.00                    | N.A.                     | 54.00                    | H   | PASS    |

**Test Result: PASS**

## Annex A Photographs of Test Setup

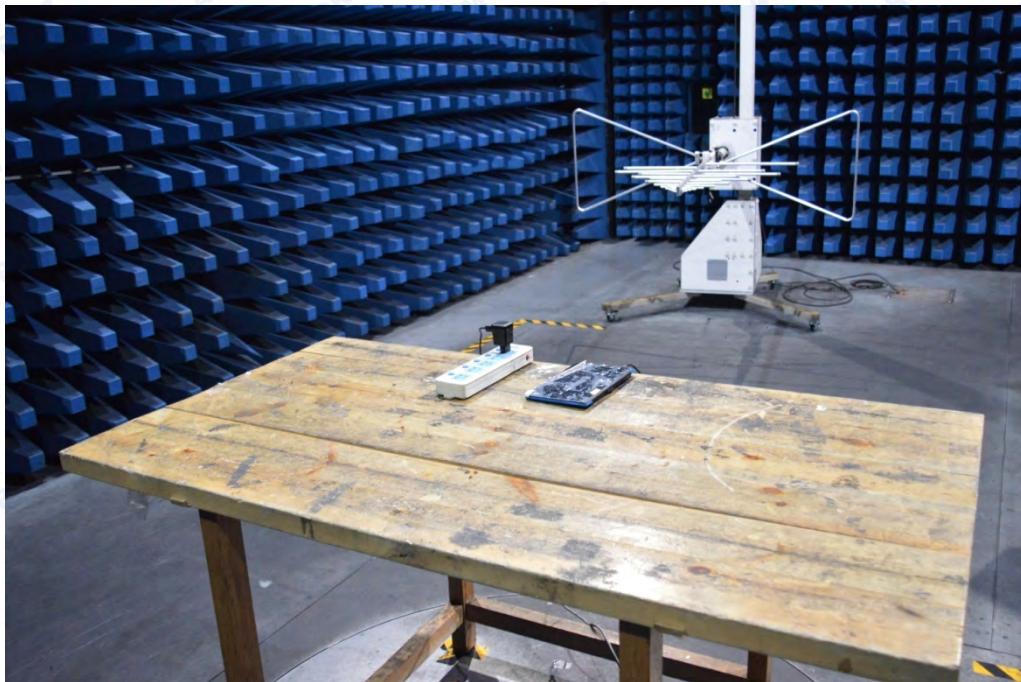
### 1. Conducted emission main's port side view



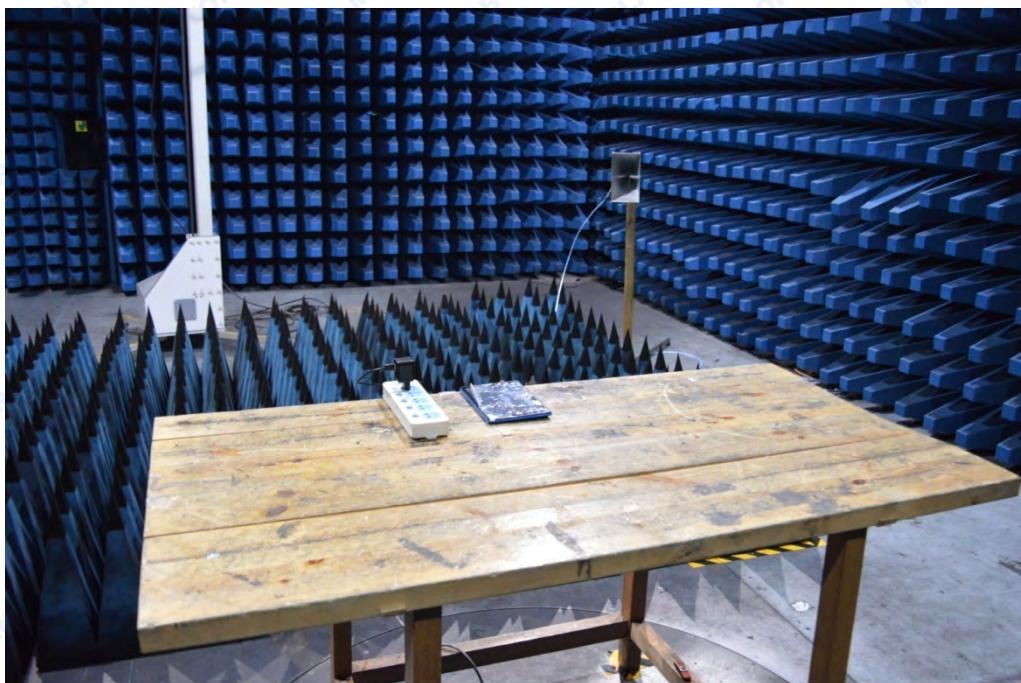
### 2. Conducted emission main's port side view



### 3. Radiated emission (30MHz-1GHz)



### 4. Radiated emission (Above 1GHz)





## Annex B Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

|                                    |        |
|------------------------------------|--------|
| Uncertainty of Conducted Emission: | ±1.8dB |
| Uncertainty of Radiated Emission:  | ±3.1dB |



## Annex C Testing Laboratory Information

### 1. Identification of the Responsible Testing Laboratory

|                               |  |
|-------------------------------|--|
| Company Name:                 | Shenzhen Morlab Communications Technology Co., Ltd.  |
| Department:                   | Morlab Laboratory  |
| Address:                      | FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District, ShenZhen, GuangDong Province, P. R. China |
| Responsible Test Lab Manager: | Mr. Su Feng  |
| Telephone:                    | +86 755 36698555   |
| Facsimile:                    | +86 755 36698525   |

### 2. Identification of the Responsible Testing Location

|          |  |
|----------|--|
| Name:    | Shenzhen Morlab Communications Technology Co., Ltd.<br>Morlab Laboratory   |
| Address: | FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District, ShenZhen, GuangDong Province, P. R. China |

### 3. Accreditation Certificate

Accredited Testing Laboratory: The FCC registration number is 695796.  
(Shenzhen Morlab Communications Technology Co., Ltd.)

### 4. Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

|                             |          |
|-----------------------------|----------|
| Temperature (°C):           | 15 - 35  |
| Relative Humidity (%):      | 30 - 60  |
| Atmospheric Pressure (kPa): | 86 - 106 |

\*\*\*\*\* END OF REPORT \*\*\*\*\*